

Date Created : 2009/01/13  
Date Issued On : 2009/08/13  
PCN# : Q1090304

DESIGN/PROCESS CHANGE NOTIFICATION -- FINAL

This is to inform you that a design and/or process change will be made to the following product(s). This notification is for your information and concurrence.

If you require data or samples to qualify this change, please contact **Fairchild Semiconductor within 30 days of receipt of this notification.**

Updated process quality documentation, such as FMEAs and Control Plans, are available for viewing upon request.

If you have any questions concerning this change, please contact:

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Implementation of change:  
Expected 1st Device Shipment Date: 2009/11/09

Earliest Year/Work Week of Changed Product: 0946

Change Type Description: Alternate Fab Location, Backside Condition, Metallization Material, Wafer Diameter

Description of Change (From): Selected Schottky Diode products that are currently manufactured using the 6-inch line at More Power Electronics Corporation (MPEC). The current Top Metallization and Backside Condition use TiNiAg material.

Description of Change (To): Selected Schottky Diode products will be manufactured using the 5-inch line at Taiwan Semiconductor Company Ltd. (TSC). The new Top Metallization and Backside Condition will use using TiNiAu material.

Reason for Change : Transfer to Taiwan Semiconductor Company Ltd. (TSC) due to shutdown of More Power Electronics Corporation (MPEC).

Qual/REL Plan Numbers : Q20090028

Qualification :

The qualification results meet all our criteria for qualifying fabrication site and the overall reliability of our products.

**Results/Discussion for Qual Plan Number Q20090028**

Test: (Charged Device Model ESD)   Conditions: >2000V   Standard: JESD22-C101			
Lot	Device	Results	Failure Code
Q20090028AACDM	FDfMA2P857	0/3	
Q20090028ABCDM	FDfMA2P857	0/3	

Q20090028BACDM	DFMJ2P023Z	0/3			
<b>Test: (High Temperature Reverse Bias)   Conditions: 150C, 24V   Standard: JESD22-A108</b>					
Lot	Device	500-HOURS	1000-HOURS	Failure Code	
Q20090028BAHTRB	DFMJ2P023Z	0/79			
Q20090028BAHTRB	DFMJ2P023Z		0/79		
<b>Test: (High Temperature Reverse Bias)   Conditions: 85C, 24V   Standard: JESD22-A108</b>					
Lot	Device	500-HOURS	1000-HOURS	Failure Code	
Q20090028AAHTRB	DFMA2P857	0/79			
Q20090028AAHTRB	DFMA2P857		0/79		
Q20090028ABHTRB	DFMA2P857	0/79			
Q20090028ABHTRB	DFMA2P857		0/79		
<b>Test: (High Temperature Storage Life)   Conditions: 150C   Standard: JESD22-A103</b>					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090028AAHTSL		0/79			
			0/79		
				0/79	
Q20090028BAHTSL	DFMJ2P023Z	0/79			
			0/79		
				0/79	
<b>Test: (Human Body Model ESD)   Conditions: &gt;8000V   Standard: JESD22-A114</b>					
Lot	Device	Results	Failure Code		
Q20090028AAHBM	DFMA2P857	0/3			
Q20090028ABHBM	DFMA2P857	0/3			
Q20090028BAHBM	DFMJ2P023Z	0/3			
<b>Test: (Moisture Sensitivity)   Conditions:   Standard: J-STD_020</b>					
Lot	Device	Results	Failure Code		
Q20090028AAMS LNL1A	DFMA2P857	0/22			
Q20090028ABMS LNL1A	DFMA2P857	0/22			
Q20090028BAMS LNL1A	DFMJ2P023Z	0/22			
<b>Test: (Physical Dimensions)   Conditions:   Standard: JESD22-B100</b>					
Lot	Device	Results	Failure Code		
Q20090028BAPHYD	DFMJ2P023Z	0/30			
<b>Test: (Precondition)   Conditions:   Standard: JESD22-A113</b>					
Lot	Device	Results	Failure Code		
Q20090028AAPCNL1A	DFMA2P857	0/158			
Q20090028ABPCNL1A	DFMA2P857	0/158			
Q20090028BAPCNL1A	DFMJ2P023Z	0/158			
<b>Test: (Temperature Cycle)   Conditions: -65C, 150C   Standard: JESD22-A104</b>					
Lot	Device	100-CYCLES	500-CYCLES	Failure Code	
Q20090028AATMCL1	DFMA2P857	0/79			
Q20090028AATMCL1	DFMA2P857		0/79		
Q20090028ABTMCL1	DFMA2P857	0/79			
Q20090028ABTMCL1	DFMA2P857		0/79		
Q20090028BATMCL1	DFMJ2P023Z	0/79			
Q20090028BATMCL1	DFMJ2P023Z		0/79		
<b>Test: (Temperature Humidity Biased Test)   Conditions: 85%RH, 85C, 24V   Standard: JESD22-A101</b>					
Lot	Device	168-HOURS	500-HOURS	1000-HOURS	Failure Code
Q20090028AATHBT	DFMA2P857	0/79			
			0/79		
				0/79	
Q20090028ABTHBT		0/79			
			0/79		
				0/79	
Q20090028BATHBT	DFMJ2P023Z	0/79			
			0/79		
				0/79	

Product Id Description : Fairchild Semiconductor's selected Schottky Diode products that are currently manufactured using the 6-inch line at More Power Electronics Corporation (MPEC).

Affected FSIDs :

DFMA2P857	DFMJ2P023Z	
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